DAHLBERG – Appl. No. 10/699,932

Amendments to the Specification

Please replace the paragraph on page 6, lines 10-17 with the following amended paragraph:

The disclosed control register 102 provides an offset value and a bit that controls whether the offset value is added to or subtracted from the delay value 106 determined by the DLL 100. With these modifications, an additional controller (hardware or software, not shown) may be added to run a memory test while adding and subtracting various offsets 110 11 to determine the limits of failure free operation. The final offset 110 11 to be used in normal operation is preferably the one in the middle of the limits in which the memory test passes.

Please replace the paragraph on page 6, lines 23-28 with the following amended paragraph:

One important advantage provided by this embodiment of the present invention is that the data strobe (DQS) delay can be tweaked by the addition or subtraction of a fine adjustment offset **110 11**, to allow it to be positioned closer to the actual, optimal center of the data eye. This results in more reliable memory operations, as well as a higher frequency of operation.

DAHLBERG – Appl. No. 10/699,932

Please replace the paragraph on page 7, lines 4-19 with the following amended paragraph:

In particular, Fig. 2 shows a modification to the circuit shown in Fig. 1 wherein a PVT circuit 200 is added to compensate for changes in the tweaked delay value providing offset 110 11 due to fluctuations in voltage and PVT circuits are known, and provide information about the operating conditions (process, voltage, and temperature) of a device in a system. The PVT circuit 200 outputs another fine adjustment offset output value 211 that indicates the current operating conditions of the device. The PVT fine adjustment offset output value 211 will vary as the actual voltage and/or temperature changes. The PVT fine adjustment offset output value 211 is also affected by actual variations in the device process manufacturing, which can be considered a constant for any given instance of a device. As applied to the present invention, the PVT circuit 200 corrects the offset delay 110 provided by the DLL 100a, and the offset 110 11 provided by the control register 102, keeping the overall actual delay offset relatively constant as the voltage and/or temperature of the DDR read data capture circuit actually varies over time.